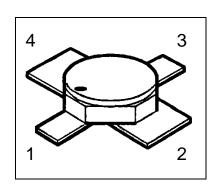


HiRel NPN Silicon Germanium RF Transistor

- HiRel Discrete and Microwave Semiconductor
- For high power amplifiers
- Ideal for low phase noise oscilators
- Maximum available gain: G_{ma} = 19 dB at 1.8 GHz
 Noise figure F = 0.9 dB at 1.8 GHz
- Hermetically sealed microwave package
- Cesa Space Qualified

ESCC Detail Spec. No.: 5611/010



ESD: Electrostatic discharge sensitive device, observe handling precautions!

Туре	Marking	Pin Configuration Package 1 2 3 4			Pin Configuration		
		1	2	3	4		
BFY650B-11	-	С	Е	В	Е	Micro-X	

Maximum Ratings

Parameter	Symbol	Values	Unit	
Collector-emitter voltage $T_a > 0 ^{\circ}C$ $T_a \leq 0 ^{\circ}C$	V _{CEO}	4.0 3.7	V	
Collector-base voltage	V _{CBO}	13	V	
Emitter-base voltage	V _{EBO}	1.2	V	
Collector current 1)	Ic	150	mA	
Base current	I _B	10	mA	
Junction temperature	T _j	175	°C	
Operating temperature range	T _{op}	-65+175	°C	
Storage temperature range	T _{stg}	-65+175	°C	
Thermal Resistance	•	•	,	
Junction-soldering point 2)	R _{th JS}	150	K/W	

Notes.:

- 1) For $T_S \le 85^{\circ}C$. For $T_S > 85^{\circ}C$ derating is required.
- 2) T_S is measured on the emitter lead at the soldering point to the pcb.



Electrical Characteristics

at T_A=25°C; unless otherwise specified

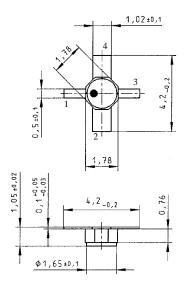
Parameter	Symbol	Values			Unit
		min.	typ.	max.	
DC Characteristics	·		•		
Collector-base cutoff current	I _{CBO}	-	-	10	μΑ
$V_{CB} = 5 \text{ V}, I_E = 0$					
Collector-emitter cutoff current 1)	I _{CEX}	-	-	200	μΑ
$V_{CE}=4.0~V,~I_{B}=0.1~\mu A$					
Emitter-base cuttoff current	I _{EBO}	-	-	10	μА
$V_{EB} = 1.2 \text{ V}, I_{C} = 0$					
DC current gain	h _{FE}	110	180	270	-
$I_C = 80$ mA, $V_{CE} = 3$ V					
AC Characteristics	•		•		-
Collector-base capacitance	C _{CB}	-	0.26	-	pF
$V_{CB} = 2 \text{ V}, V_{BE} = \text{vbe} = 0, f = 1 \text{ MHz}$					
Collector-emitter capacitance	C _{CE}	-	0.55	-	pF
$V_{CE} = 2 \text{ V}, V_{BE} = \text{vbe} = 0, f = 1 \text{ MHz}$					
Emitter-base capacitance	C _{EB}	-	1.4	-	pF
$V_{EB} = 0.5V$, $V_{CB} = vcb = 0$, $f = 1 MHz$					
Noise Figure ($Z_S = Z_{sopt}$)	F				dB
$I_C = 10 \text{ mA}, V_{CE} = 3 \text{ V}, f = 1.8 \text{ GHz}$		-	0.9	-	
$I_C = 10 \text{ mA}, V_{CE} = 3 \text{ V}, f = 6.0 \text{ GHz}$	12 12	-	1.4	-	<u> </u>
Insertion power gain ($Z_S = Z_L = 50 \Omega$)	$ S_{21e} ^2$				dB
$I_{C} = 80$ mA, $V_{CE} = 3$ V, $f = 1.8$ GHz $I_{C} = 80$ mA, $V_{CE} = 3$ V, $f = 6.0$ GHz		-	16.5 6.7	-	
Power gain $(Z_S = Z_{Sopt}, Z_L = Z_{Lopt})$	G _{ma} ²⁾				dB
$I_C = 80 \text{ mA}, V_{CE} = 3 \text{ V}, f = 1.8 \text{ GHz}$		-	19.2	-	
Power gain ($Z_S = Z_{Sopt}$, $Z_L = Z_{Lopt}$)	G _{ma} ²⁾				dB
$I_C = 80 \text{ mA}, V_{CE} = 3 \text{ V}, f = 6.0 \text{ GHz}$		-	9.3	-	

2)
$$G_{ma} = \left| \frac{S21}{S12} \right| (k - \sqrt{k^2 - 1}), \quad G_{ms} = \left| \frac{S21}{S12} \right|$$

Notes.:
1) This Test assures V(BR)CE0 > 4.0V



Micro-X Package



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